

Search Notes 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/787,015	CHIN ET AL.	
				Examiner	Art Unit	
				David M. Naff	1651	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
				<i>West</i> <i>See printout</i>	<i>10/2/06</i>	<i>an</i>
				<i>to do</i>	<i>4/14/07</i>	<i>an</i>
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			